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Application/Control No.	Applicant(s)/Patent under Reexamination
10/767,230	OHNISHI ET AL.
Examiner	Art Unit
Andy Huynh	2818

	SEARCHED			
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST (text search-see search history printout)	7/27/2005	АН	
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